

N- and P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY				
	V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)
N-Channel	20	0.060 at V _{GS} = 4.5 V	4.5 ^a	3.5 nC
		0.092 at V _{GS} = 2.5 V	4.5 ^a	
P-Channel	- 20	0.110 at V _{GS} = - 4.5 V	- 4.5 ^a	3 nC
		0.185 at V _{GS} = - 2.5 V	- 4.5 ^a	

FEATURES

- Halogen-free
- TrenchFET[®] Power MOSFETs
- New Thermally Enhanced PowerPAK[®] SC-70 Package
 - Small Footprint Area
 - Low On-Resistance

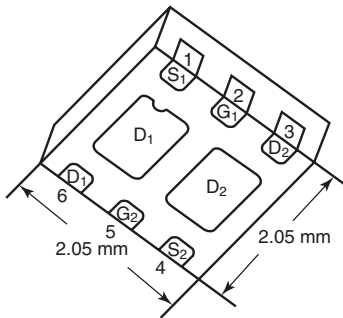


RoHS
COMPLIANT

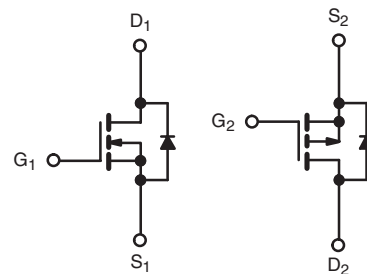
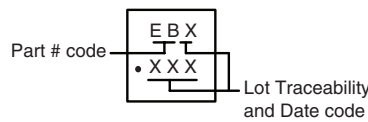
APPLICATIONS

- Portable Devices

PowerPAK SC-70-6 Dual



Marking Code



Ordering Information: SiA513DJ-T1-GE3 (Lead (Pb)-free and Halogen-free)

N-Channel MOSFET P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted				
Parameter	Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage	V _{DS}	20	- 20	V
Gate-Source Voltage	V _{GS}	± 12		
Continuous Drain Current (T _J = 150 °C)	I _D	T _C = 25 °C	4.5 ^a	- 4.5 ^a
		T _C = 70 °C	4.5 ^a	- 4.5 ^a
		T _A = 25 °C	4.5 ^{a, b, c}	- 3.3 ^{b, c}
		T _A = 70 °C	3.2 ^{b, c}	- 2.4 ^{b, c}
Pulsed Drain Current	I _{DM}	15	- 10	A
Source Drain Current Diode Current	I _S	T _C = 25 °C	4.5 ^a	
		T _A = 25 °C	1.6 ^{b, c}	- 1.6 ^{b, c}
Maximum Power Dissipation	P _D	T _C = 25 °C	6.5	6.5
		T _C = 70 °C	5	5
		T _A = 25 °C	1.9 ^{b, c}	1.9 ^{b, c}
		T _A = 70 °C	1.2 ^{b, c}	1.2 ^{b, c}
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150		°C
Soldering Recommendations (Peak Temperature) ^{d, e}		260		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	N-Channel		P-Channel		Unit
			Typ.	Max.	Typ.	Max.	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 5 s	R _{thJA}	52	65	52	65	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	12.5	16	12.5	16	

Notes:

a. Package limited.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. See Solder Profile (<http://www.vishay.com/ppg?73257>). The PowerPAK SC-70 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under Steady State conditions is 110 °C/W.

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	N-Ch	20		V	
		$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	P-Ch	-20			
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250\text{ }\mu\text{A}$	N-Ch		22	mV/ $^\circ\text{C}$	
		$I_D = -250\text{ }\mu\text{A}$	P-Ch		-16		
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250\text{ }\mu\text{A}$	N-Ch		-3.5		
		$I_D = -250\text{ }\mu\text{A}$	P-Ch		2.5		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	N-Ch	0.6		1.5	V
		$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	P-Ch	-0.6		-1.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 12\text{ V}$	N-Ch			± 100	nA
			P-Ch			± 100	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$	N-Ch			1	μA
		$V_{DS} = -20\text{ V}, V_{GS} = 0\text{ V}$	P-Ch			-1	
		$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$	N-Ch			10	
		$V_{DS} = -20\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$	P-Ch			-10	
On-State Drain Current ^b	$I_{D(on)}$	$V_{DS} \geq 5\text{ V}, V_{GS} = 4.5\text{ V}$	N-Ch	10			A
		$V_{DS} \leq -5\text{ V}, V_{GS} = -4.5\text{ V}$	P-Ch	-5			
Drain-Source On-State Resistance ^b	$R_{DS(on)}$	$V_{GS} = 4.5\text{ V}, I_D = 3.4\text{ A}$	N-Ch		0.050	0.060	Ω
		$V_{GS} = -4.5\text{ V}, I_D = -2.5\text{ A}$	P-Ch		0.091	0.110	
		$V_{GS} = 2.5\text{ V}, I_D = 1.1\text{ A}$	N-Ch		0.076	0.092	
		$V_{GS} = -2.5\text{ V}, I_D = -0.54\text{ A}$	P-Ch		0.152	0.185	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 10\text{ V}, I_D = 3.4\text{ A}$	N-Ch		8		S
		$V_{DS} = -10\text{ V}, I_D = -2.5\text{ A}$	P-Ch		3.5		
Dynamic^a							
Input Capacitance	C_{iss}	N-Channel $V_{DS} = 10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	N-Ch		360		pF
			P-Ch		250		
Output Capacitance	C_{oss}	P-Channel $V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	N-Ch		70		pF
			P-Ch		70		
Reverse Transfer Capacitance	C_{rss}		N-Ch		40		pF
			P-Ch		45		
Total Gate Charge	Q_g	$V_{DS} = 10\text{ V}, V_{GS} = 10\text{ V}, I_D = 4.5\text{ A}$	N-Ch		7.5	12	nC
		$V_{DS} = -10\text{ V}, V_{GS} = -10\text{ V}, I_D = -3.3\text{ A}$	P-Ch		6	9	
Gate-Source Charge	Q_{gs}	N-Channel $V_{DS} = 10\text{ V}, V_{GS} = 4.5\text{ V}, I_D = 4.5\text{ A}$	N-Ch		3.5	5.3	
			P-Ch		3	4.5	
Gate-Drain Charge	Q_{gd}	P-Channel $V_{DS} = -10\text{ V}, V_{GS} = -4.5\text{ V}, I_D = -3.3\text{ A}$	N-Ch		0.9		
			P-Ch		0.7		
Gate Resistance	R_g	$f = 1\text{ MHz}$	N-Ch		2.5		Ω
			P-Ch		8		

Notes:

- a. Guaranteed by design, not subject to production testing.
b. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.



SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Dynamic^a							
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 10\text{ V}$, $R_L = 2.8\ \Omega$ $I_D \cong 3.6\text{ A}$, $V_{GEN} = 4.5\text{ V}$, $R_g = 1\ \Omega$	N-Ch		10	15	ns
Rise Time	t_r		P-Ch		20	30	
Turn-Off Delay Time	$t_{d(off)}$	P-Channel $V_{DD} = -10\text{ V}$, $R_L = 3.9\ \Omega$ $I_D \cong -2.6\text{ A}$, $V_{GEN} = -4.5\text{ V}$, $R_g = 1\ \Omega$	N-Ch		20	30	
Fall Time	t_f		P-Ch		15	25	
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 10\text{ V}$, $R_L = 2.8\ \Omega$ $I_D \cong 3.6\text{ A}$, $V_{GEN} = 10\text{ V}$, $R_g = 1\ \Omega$	N-Ch		5	10	
Rise Time	t_r		P-Ch		4	8	
Turn-Off Delay Time	$t_{d(off)}$	P-Channel $V_{DD} = -10\text{ V}$, $R_L = 3.9\ \Omega$ $I_D \cong -2.6\text{ A}$, $V_{GEN} = -10\text{ V}$, $R_g = 1\ \Omega$	N-Ch		15	25	
Fall Time	t_f		P-Ch		12	20	
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 10\text{ V}$, $R_L = 2.8\ \Omega$ $I_D \cong 3.6\text{ A}$, $V_{GEN} = 10\text{ V}$, $R_g = 1\ \Omega$	N-Ch		15	25	
Rise Time	t_r		P-Ch		12	20	
Turn-Off Delay Time	$t_{d(off)}$	P-Channel $V_{DD} = -10\text{ V}$, $R_L = 3.9\ \Omega$ $I_D \cong -2.6\text{ A}$, $V_{GEN} = -10\text{ V}$, $R_g = 1\ \Omega$	N-Ch		15	25	
Fall Time	t_f		P-Ch		12	20	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$	N-Ch			4.5	A
			P-Ch			-4.5	
Pulse Diode Forward Current ^a	I_{SM}		N-Ch			15	A
			P-Ch			-10	
Body Diode Voltage	V_{SD}	$I_S = 3.6\text{ A}$, $V_{GS} = 0\text{ V}$	N-Ch		0.8	1.2	V
		$I_S = -2.6\text{ A}$, $V_{GS} = 0\text{ V}$	P-Ch		-0.8	-1.2	
Body Diode Reverse Recovery Time	t_{rr}	N-Channel $I_F = 3.6\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^\circ\text{C}$	N-Ch		15	30	ns
			P-Ch		20	40	
Body Diode Reverse Recovery Charge	Q_{rr}	N-Channel $I_F = 3.6\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^\circ\text{C}$	N-Ch		10	20	nC
			P-Ch		10	20	
Reverse Recovery Fall Time	t_a	P-Channel $I_F = -2.6\text{ A}$, $di/dt = -100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^\circ\text{C}$	N-Ch		10		ns
			P-Ch		8		
Reverse Recovery Rise Time	t_b		N-Ch		5		
			P-Ch		12		

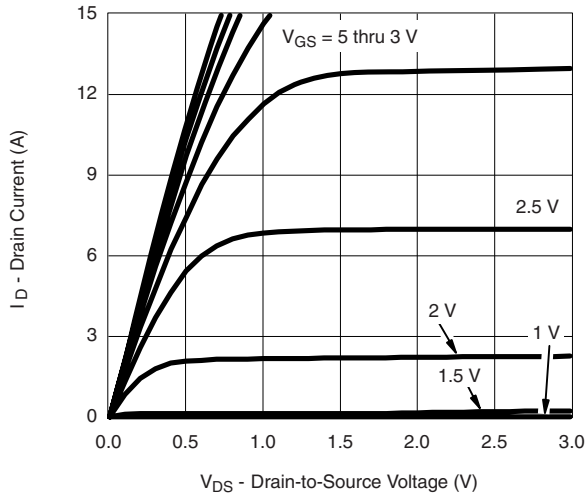
Notes:

- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.

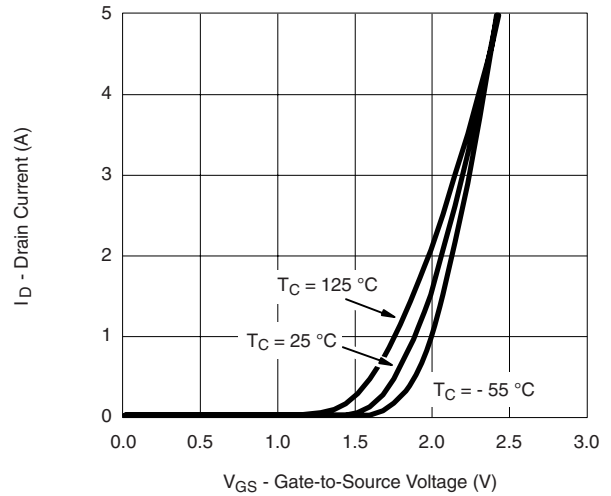
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



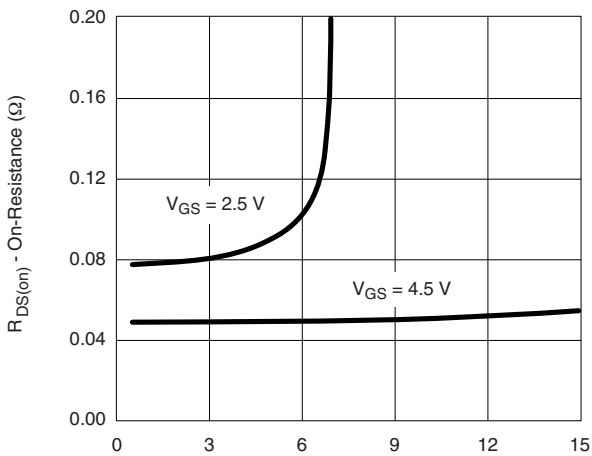
N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



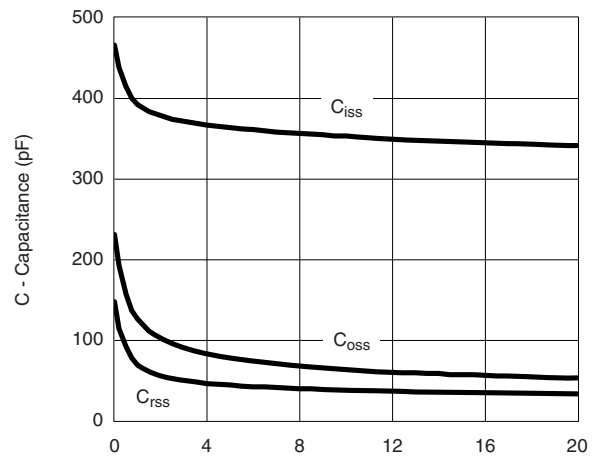
Output Characteristics



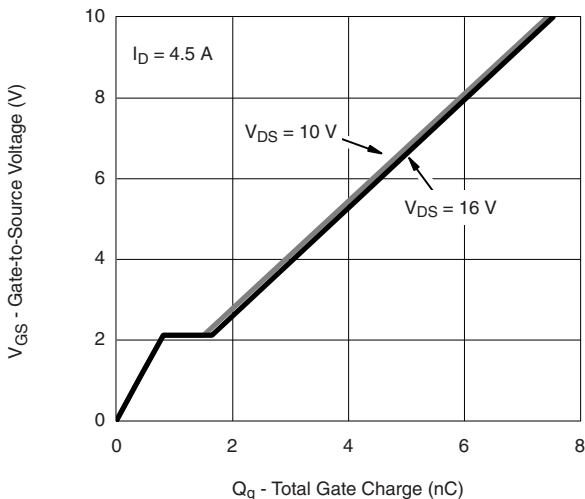
Transfer Characteristics



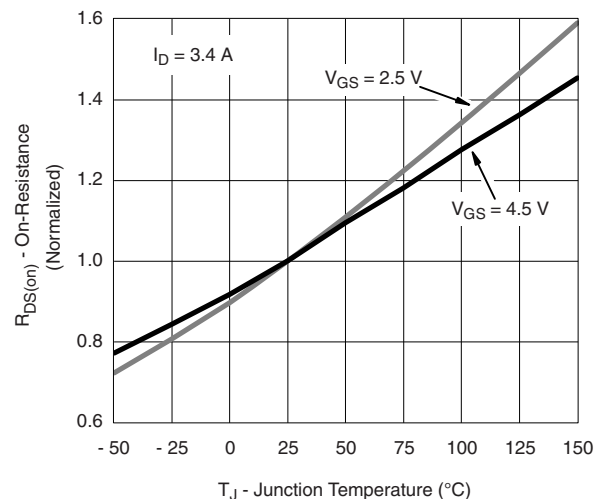
On-Resistance vs. Drain Current



Capacitance

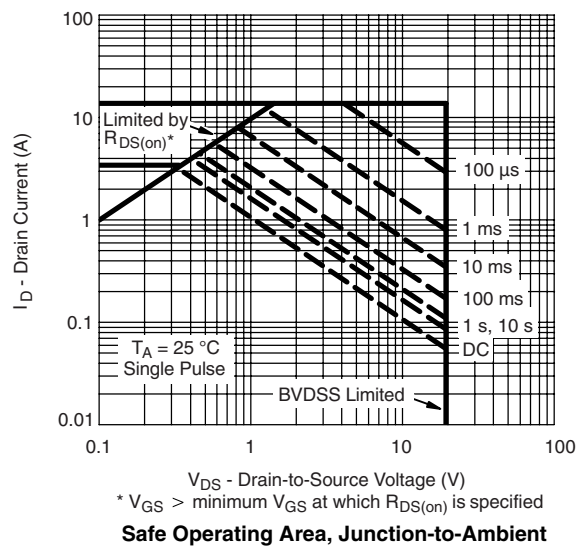
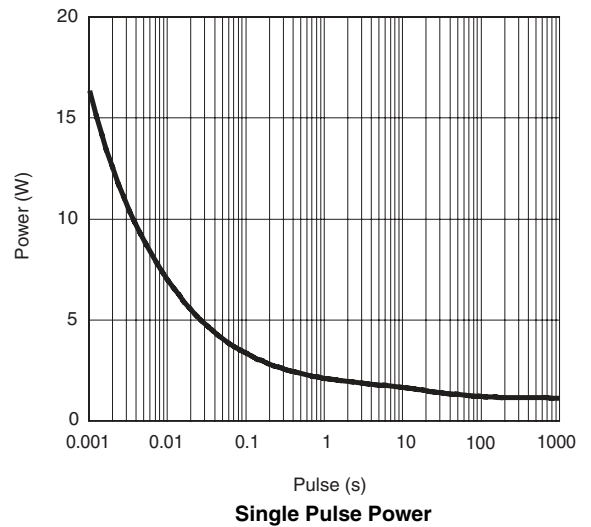
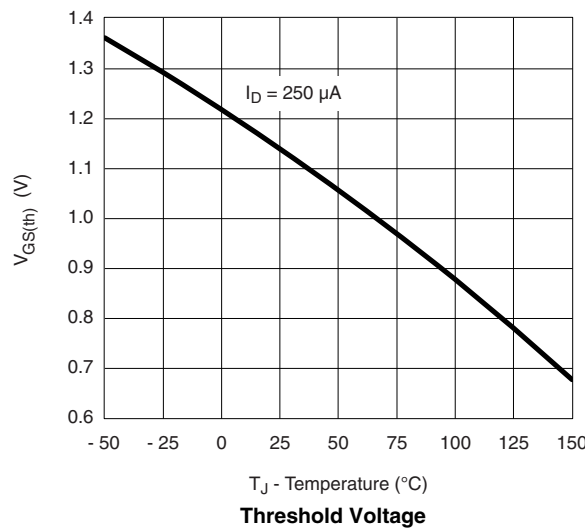
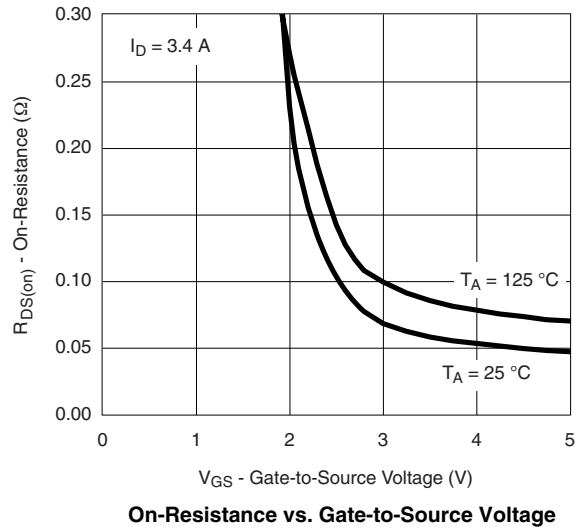
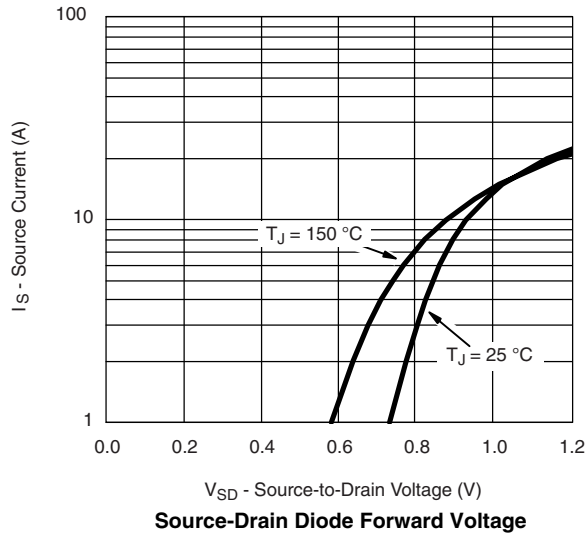


Gate Charge



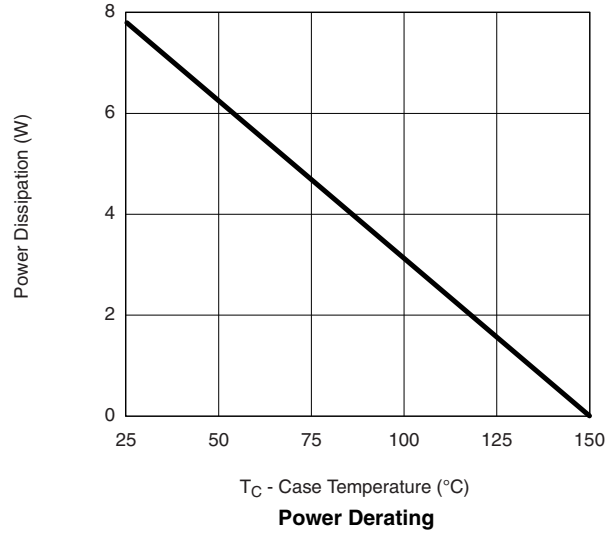
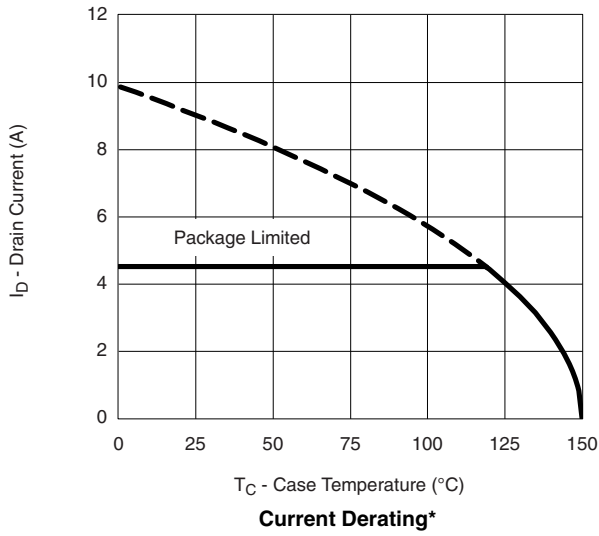
On-Resistance vs. Junction Temperature

N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





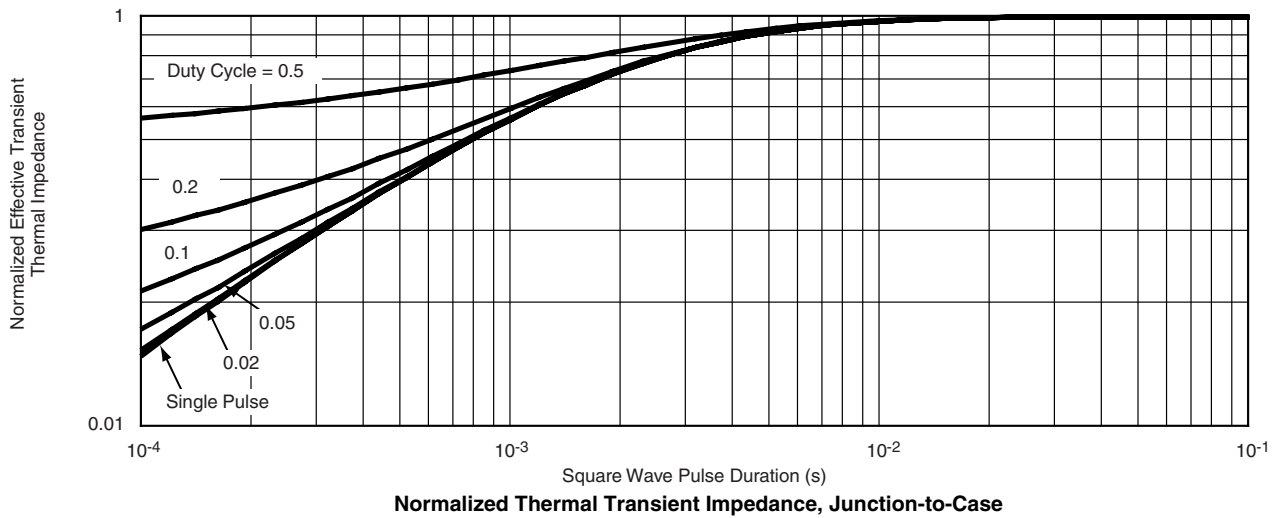
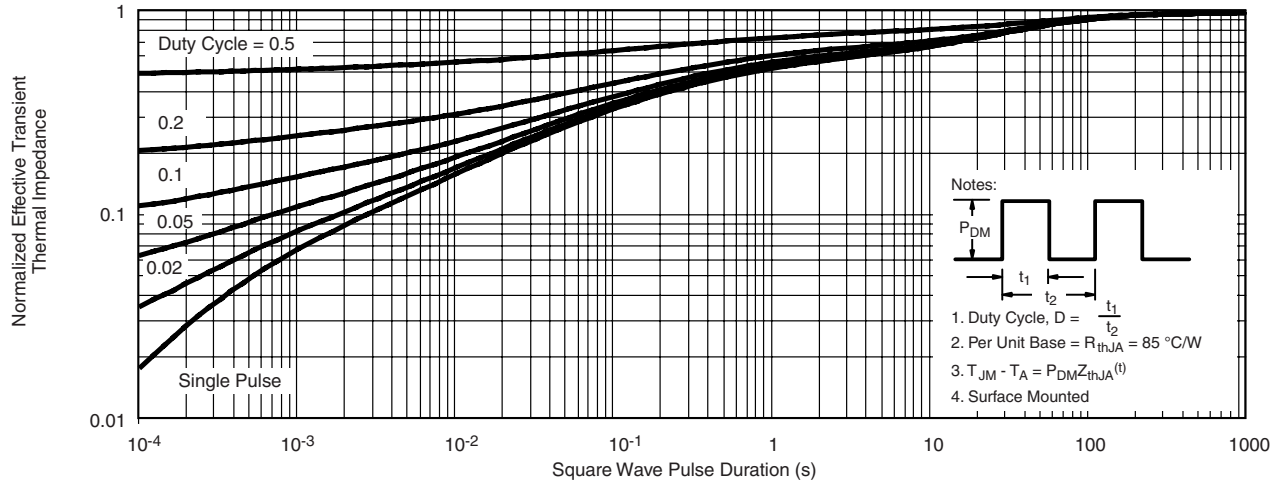
N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

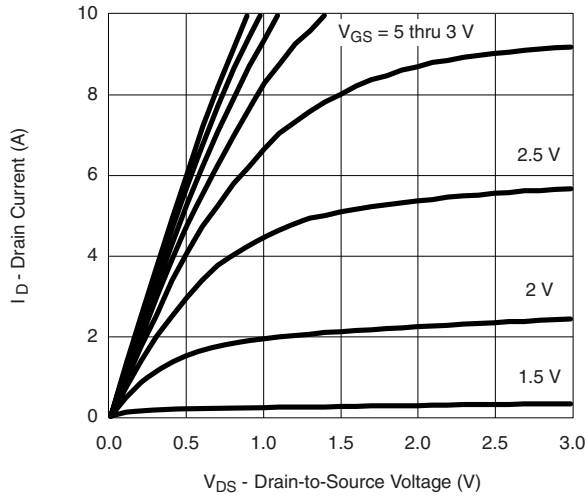


N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

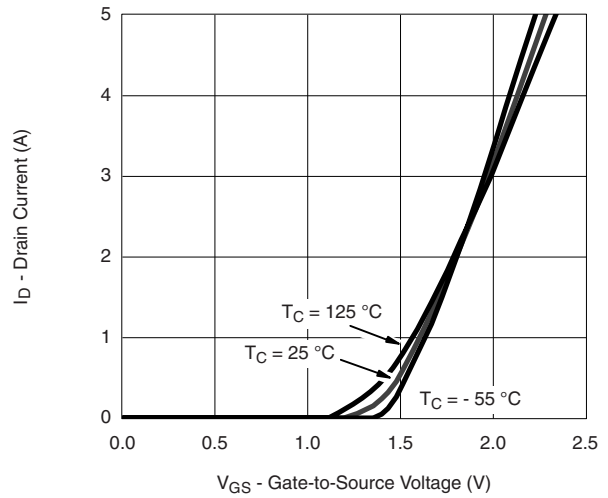




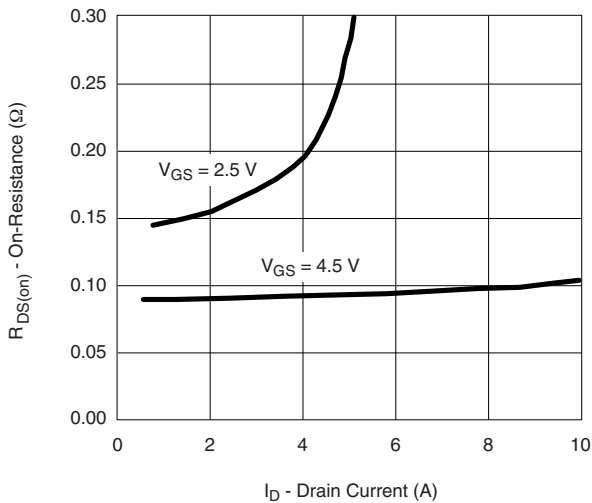
P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



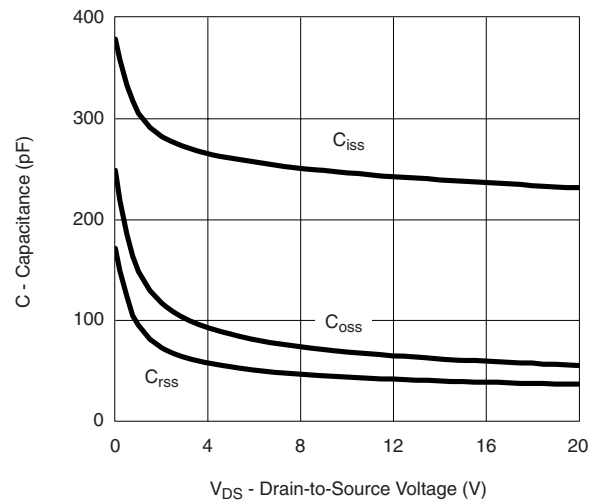
Output Characteristics



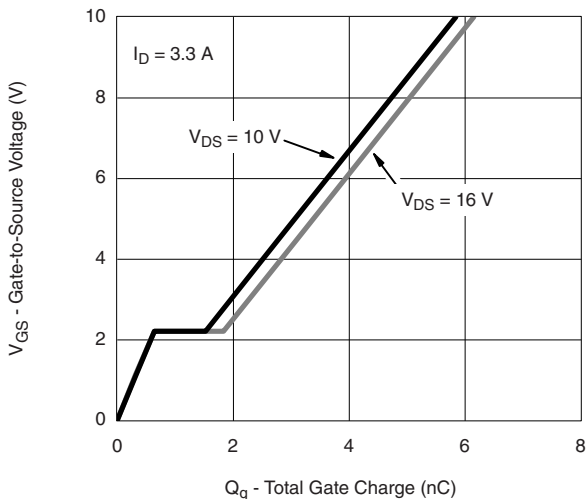
Transfer Characteristics



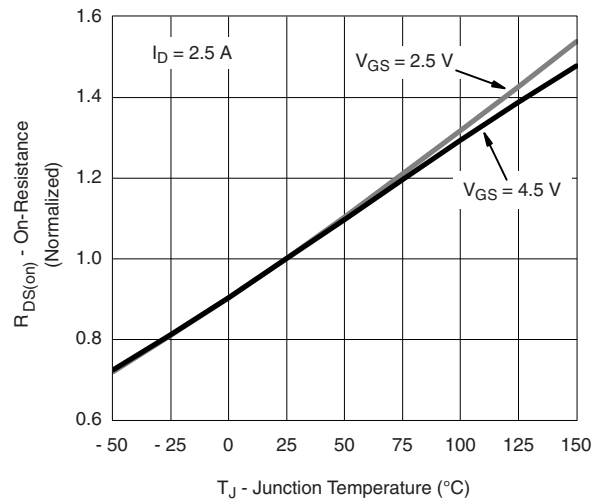
On-Resistance vs. Drain Current



Capacitance



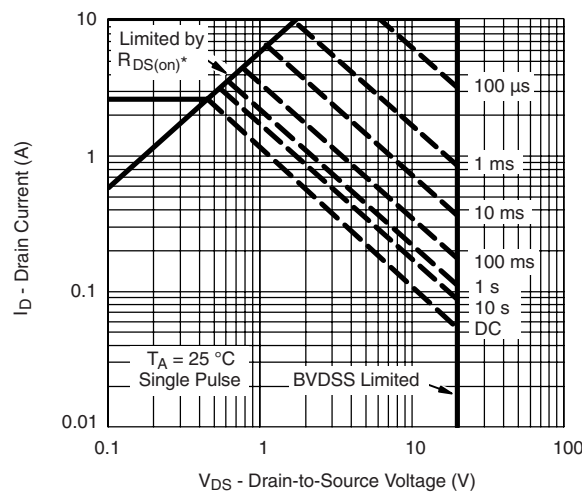
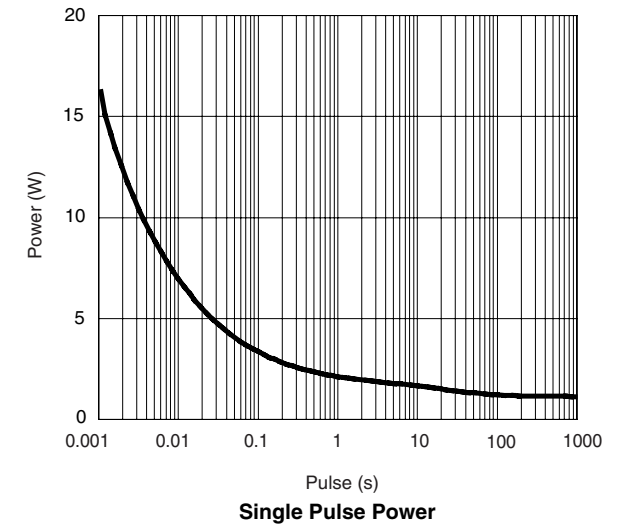
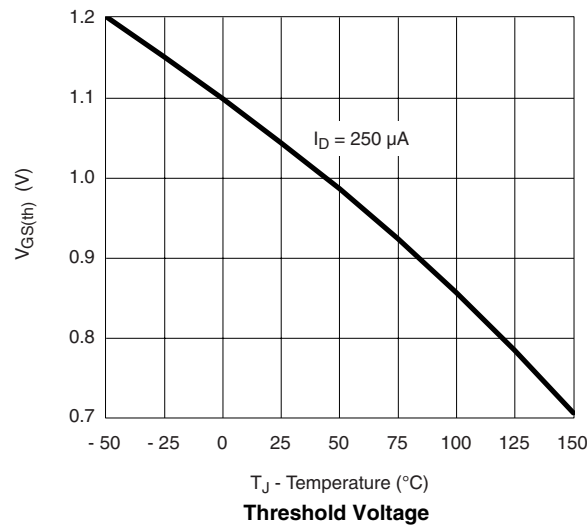
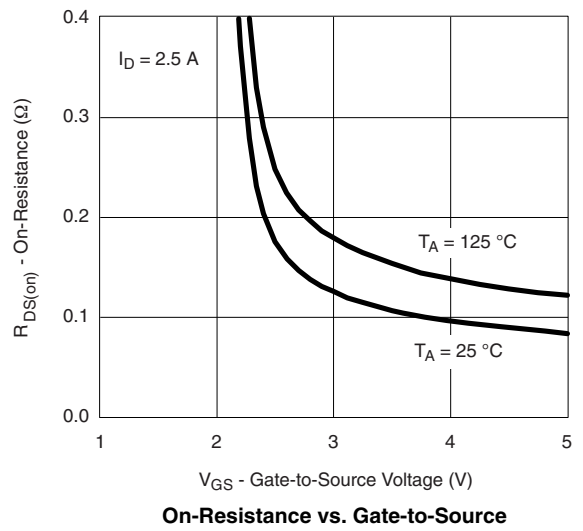
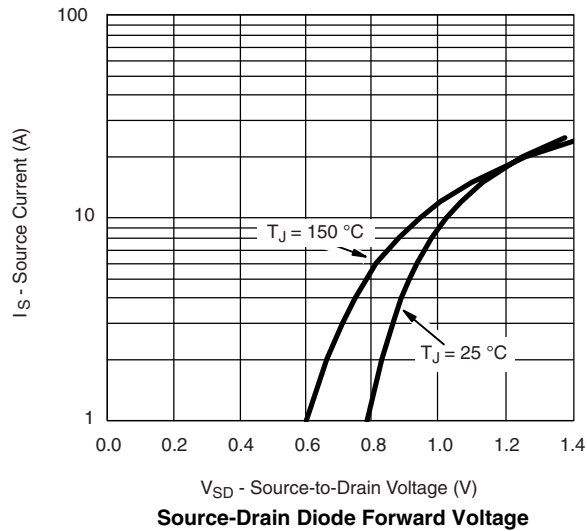
Gate Charge



On-Resistance vs. Junction Temperature



P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

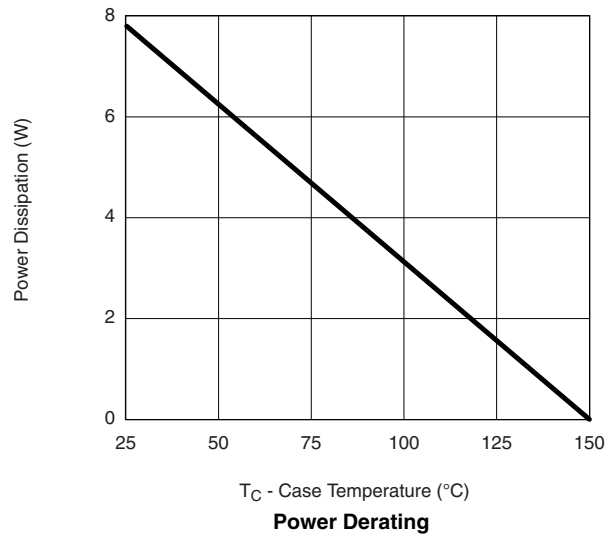
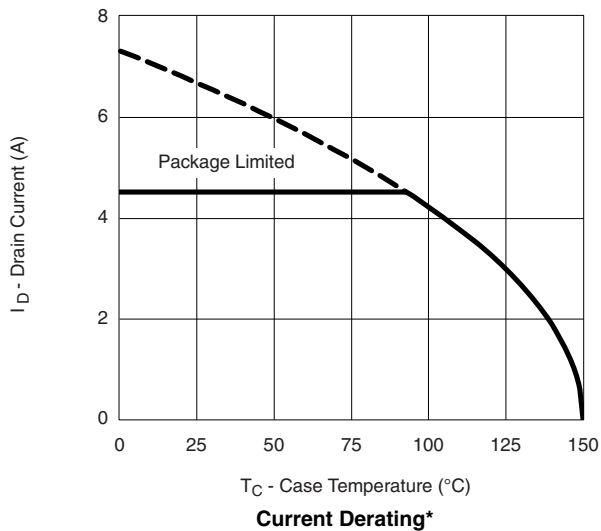


* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient



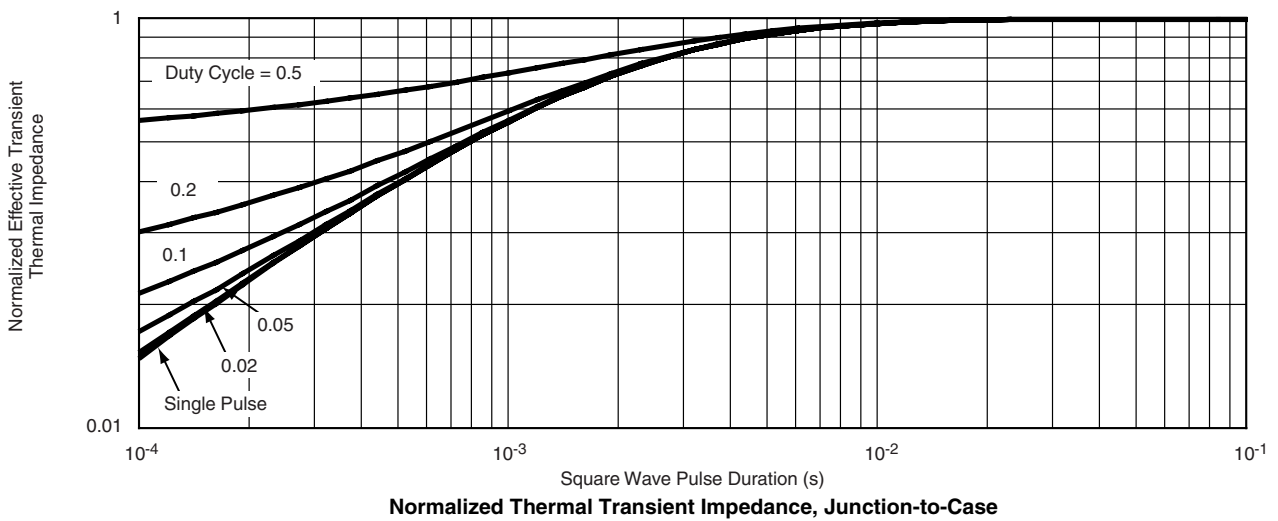
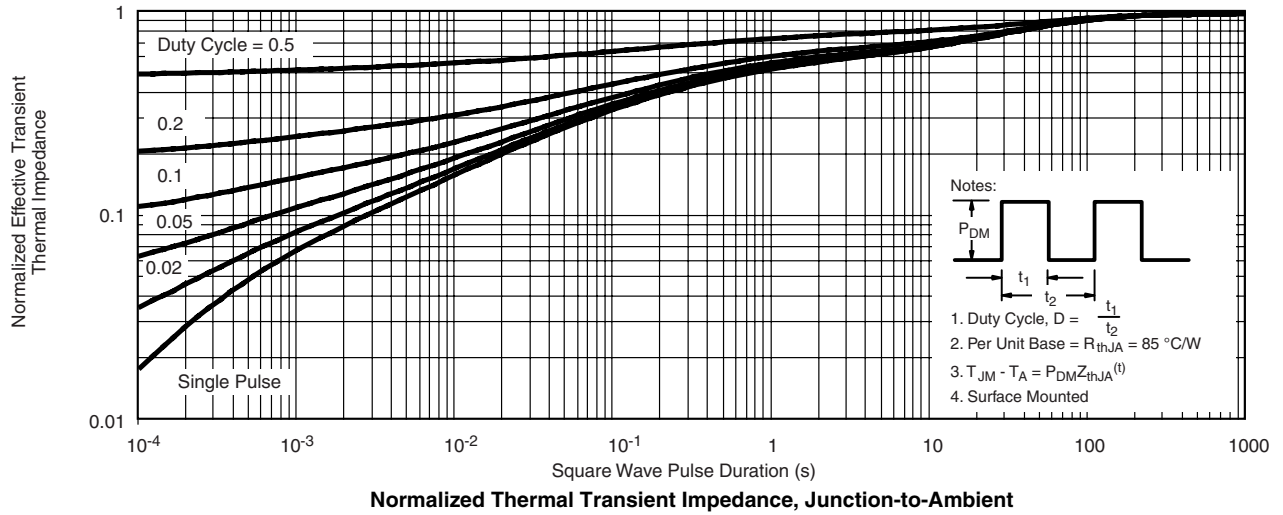
P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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